

ABSTRACT

The present application provides a test circuit. The circuit includes: an input terminal, a processing circuit and an output terminal. The input terminal is configured to receive an input signal. The input signal includes a test command to instruct to test a target circuit module and an address of the target circuit module. The processing circuit is configured to determine a test mode signal according to the test command and the address of the target circuit module. The test mode signal carries a test type. The test mode signal is used to trigger the target circuit module to perform a test corresponding to the test type. The output terminal is configured to send the test mode signal to the target circuit module according to the address of the target circuit module. Thus, the test mode signal can be accurately transmitted to different circuit modules in the memory chip.

Fig. 2